

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2822
Serial No. : 10/730,047 Examiner : Roy Karl Potter
Filed : December 9, 2003 Confirmation No.: 3013
Title : SEMICONDUCTOR CHIP AND METHOD FOR MANUFACTURING THE
SAME

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), copies of the listed U.S. patents are not enclosed and can be provided upon request.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. The fee in the amount of \$180 in payment of the late submission fee of §1.17(p) is being paid concurrently herewith on the Electronic Filing System (EFS) by way of Deposit Account authorization. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: January 18, 2006



John F. Hayden
Reg. No. 37,640

Customer No. 26171
Fish & Richardson P.C.
1425 K Street, N.W., 11th Floor
Washington, DC 20005-3500
Telephone: (202) 783-5070
Facsimile: (202) 783-2331

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-185001	Application No. 10/730,047
	Applicant Shunpei Yamazaki et al.		
	Filing Date December 9, 2003	Group Art Unit 2822	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,118,502	09/12/2000	Yamazaki et al.			04/20/98
	AB	6,242,758 B1	06/05/2001	Yamazaki et al.			10/22/97
	AC	6,506,681 B2	01/14/2003	Grigg et al.			12/06/00
	AD	6,589,811 B2	07/08/2003	Sayyah			09/11/01
	AE	6,737,300 B2	05/18/2004	Ding et al.			05/21/02
	AF	6,780,677 B2	08/24/2004	Imasu et al.			08/21/02
	AG	6,946,361 B2	09/20/2005	Takayama et al.			08/09/02
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	